

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant(s): ITOU et al.	Atty. Dkt.: 01-470
Serial No.: Unknown	Group Art Unit:
Filed: Concurrently herewith	Examiner:
Title: EEPROM AND EEPROM MANUFACTURING METHOD	

Commissioner for Patents  
Arlington, VA 22202

Date: September 12, 2003

**INFORMATION DISCLOSURE STATEMENT**

Sir:

Pursuant to 37 C.F.R. §1.56, the reference(s) listed on the attached Form PTO-1449 is/are being submitted for consideration by the Examiner without any admission that it/they constitute(s) statutory prior art, or without any admission that it/they contain(s) subject matter that anticipates the invention or renders the invention obvious to a person of ordinary skill in the art.

The Examiner is requested to initial the attached PTO Form-1449 and to return a copy of same to the undersigned attorney as proof that the listed reference(s) has/have been considered and made of record.

Respectfully submitted,



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FORM PTO-1449	ATTY. DKT NO.	01-470	SER. NO.
	APPLICANT	ITOU et al.	
	FILING DATE	September 12, 2003	GROUP

## REFERENCE DESIGNATION

## U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS
		4,477,825 (Corresponding to JP-A-58-115865 which is discussed on page 2 of the spec.)	Oct. 16, 1984	Yaron et al.		
		4,794,562	Dec. 27, 1988	Kato et al.		

## FOREIGN PATENT DOCUMENTS

## TRANSLATION

		DOCUMENT NUMBER	DATE	COUNTRY	NAME	CLASS	SUB CLASS	YES	NO
		JP-A-59-205763 * (Discussed on page 2 of the spec.)	11/21/84	JAPAN	.			X (Abstract)	
		JP-A-61-181168 *	8/13/86	JAPAN				X (Abstract)	

\* Full English text of the JP Document will be available in machine-translated form from JP (Japanese Patent Office) English language web site at <http://www1.ipdl.jpo.go.jp/PA1/cgi-bin/PA1INDEX>.

## OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, etc.)

		Lucero, et al., "A 16 kbit Smart 5 V-Only EEPROM with Redundancy," <u>IEEE Journal of Solid-State Circuits</u> , Vol. SC-18, No. 5, October 1983, pp. 539-544.
EXAMINER	DATE CONSIDERED	